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Application/Control No.	Applicant(s)/Patent under Reexamination
10/777,155	LAMPELL ET AL.
Examiner	Art Unit
Quynh H. Nguyen	2614

	SEAR	CHED	
Class	Subclass	Date	Examiner
379	189 114.02 190 196 197	8/3/2006	QN
above	updated	1/26/2007	QN
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INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
379	189 114.02 190 196 <b>197</b>	1/26/07	QN
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	e searched print out	1/26/07	QN

SEARCH NO' (INCLUDING SEARCH		)
	DATE	EXMR
searched:East, USPAT, USPGPub	8/3/2006	QN
inventor searched through PALM database	8/3/2006	QN
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